#### Test Beam 5-19 July 2023

## CMOS-LGAD studies



### **CMOS Passive Structures**

- First test of CMOS sensors with gain
- Test of the sensor concept (the chip readout board is going to be delivered) :
  - W6 passive structures : PM250\_G1 and PM250\_A1
- Sensor electrode AC coupled to the external amplifiers:
  - First amplification stage : modified LGAD board, G=6
  - Second amplification stage : Minicircuit amplifier, G=11.9





PM250\_A1 structure

PM250\_G1 structure



Different setup versions

- A: Multipurpose board + mezzanine + 2 Minicircuit amplifiers  $\rightarrow$  too noisy
- B: Santa Cruz Board PCB with 5 ENIG pads + multi hole board Minicircuit LEE-39+ amplifier
- **C**: Santa Cruz Board flexible PCB Minicircuit LEE-39+ amplifier



Different setup versions **B**: Santa Cruz Board – PCB with 5 ENIG pads + multi hole board – Minicircuit LEE-39+ amplifier

- Noise reduced to ~ 10-12mV ( ~ a 5 factor smaller than the previous version)
- Imposed a triple coincidence between CMOS and 2 LGAD  $\rightarrow$  ~ 10 coincidences per spill (bandwidth at 200MHz)
- Data acquisition at: 200MHz and Full Bandwidth



C: Santa Cruz Board – flexible PCB – Minicircuit LEE-39+ amplifier
Different Setup
Noise reduced to ~ 7-8mV
Imposed a triple coincidence between CMOS and 2 LGAD → ~ 8 coincidences per spill (bandwidth at 200MHz)

- Data acquisition at Full Bandwidth

# First Signals



CMOS-LGAD signals acquired at different time triggering on LGADs

 $\rightarrow$  It is possible to identify well defined waveform beyond the noise



### Offline analysis 📫 Fourier Transform



Original signal with noise  $\rightarrow$  presence of a periodic frequency

> 1.0 1e10

### Offline analysis 📫 Fourier Transform



### Offline analysis 📫 Fourier Transform



further the noise

We are studying the best process to reduce the noise and carry on the data analysis

TO BE CONTINUED...